











TPS22918-Q1

SLVSCZ8B-JULY 2016-REVISED DECEMBER 2019

# TPS22918-Q1, 5.5-V, 2-A, 52-m $\Omega$ On-Resistance Load Switch

#### **Features**

- AEC-Q100 Qualified
- Integrated single-channel load switch
- Qualified for automotive applications:
  - Device Temperature Grade 2: -40°C to +105°C ambient operating temperature range
- Functional safety capable
  - Documentation available to aid functional safety system design
- Input voltage range: 1 V to 5.5 V
- Low On-Resistance (R<sub>ON</sub>)
  - $R_{ON} = 52 \text{ m}\Omega$  (typical) at  $V_{IN} = 5 \text{ V}$
  - R<sub>ON</sub> = 53 mΩ (typical) at V<sub>IN</sub> = 3.3 V
- 2-A Maximum continuous switch current
- Low quiescent current
  - 8.3 μA (typical) at V<sub>IN</sub> = 3.3 V
- Low-control input-threshold enables use of 1 V or higher GPIO
- Configurable Quick-Output Discharge (QOD)
- Configurable rise time with CT pin
- Small SOT23-6 package (DBV)
  - 2.9 mm × 2.8 mm, 0.95-mm Pitch, 1.45-mm height (with leads)
- ESD Performance tested per AEC Q100
  - ±2-kV HBM and ±750-V CDM

### **Applications**

- Automotive electronics
- Infotainment
- Cluster
- ADAS (Advanced Driver Assistance Systems)

## 3 Description

The TPS22918-Q1 is a single-channel load switch with both configurable rise time and configurable quick-output discharge. The device contains an Nchannel MOSFET that can operate over an input voltage range of 1 V to 5.5 V and can support a maximum continuous current 2 A. The switch is controlled by an on and off input, which is capable of interfacing directly with lowvoltage control signals.

The configurable rise time of the device reduces inrush current caused by large bulk load capacitances, thereby reducing or eliminating power supply droop. The TPS22918-Q1 features a configurable quick output discharge (QOD) pin. which controls the fall time of the device to allow design flexibility for power down and sequencing.

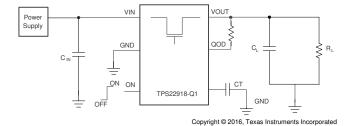
The TPS22918-Q1 is available in a small, leaded SOT-23 package (DBV) which allows to visually inspect solder joints. The device is characterized for operation over the free-air temperature range of -40°C to +105°C.

### Device Information<sup>(1)</sup>

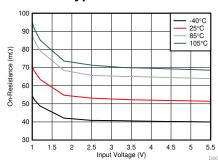
PART NUMBER	PACKAGE	BODY SIZE (NOM)
TPS22918-Q1	SOT-23 (6)	2.90 mm × 1.60 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

## Simplified Schematic



#### On-Resistance vs Input Voltage Typical Values



 $I_{OUT} = -200 \text{ mA}$ 



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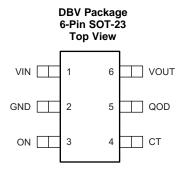
# 4 Revision History

Changes from Revision A (July 2016) to Revision B	Page
Added Functional safety capable link in the Features section	1
Changes from Original (July 2016) to Revision A	Page
Changed device status from Product Preview to Production Data	1

Product Folder Links: TPS22918-Q1



# 5 Pin Configuration and Functions



### **Pin Functions**

	PIN		25020051011			
NO.	NAME	TYPE	DESCRIPTION			
1	VIN	I	Switch input. Place ceramic bypass capacitor(s) between this pin and GND. See the <i>Detailed Description</i> section for more information			
2	GND	_	Device ground			
3	ON	1	Active high switch control input. Do not leave floating			
4	СТ	0	Switch slew rate control. Can be left floating. See the <i>Feature Description</i> section for more information			
5	QOD	0	Quick Output Discharge pin. This functionality can be enabled in one of three ways  Placing an external resistor between VOUT and QOD  Tying QOD directly to VOUT and using the internal resistor value (R <sub>PD</sub> )  Disabling QOD by leaving pin disconnected  See the Quick Output Discharge (QOD) section for more information			
6	VOUT	0	Switch output			

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## 6 Specifications

### 6.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
$V_{IN}$	Input voltage	-0.3	6	٧
V <sub>OUT</sub>	Output voltage	-0.3	6	٧
V <sub>ON</sub>	ON voltage	-0.3	6	٧
I <sub>MAX</sub>	Maximum continuous switch current, T <sub>A</sub> = 70°C (3)		2	Α
I <sub>MAX</sub>	Maximum continuous switch current, T <sub>A</sub> = 85°C (3)		1.5	Α
I <sub>PLS</sub>	Maximum pulsed switch current, pulse < 300 μs, 2% duty cycle		2.5	Α
TJ	Maximum junction temperature		150	°C
T <sub>stg</sub>	Storage temperature	-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values are with respect to network ground terminal.

### 6.2 ESD Ratings

			VALUE	UNIT
V	Flootroototic discharge	Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±2000	V
V <sub>(ESD)</sub> Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±750	V	

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

### 6.3 Recommended Operating Conditions

Over operating free-air temperature range (unless otherwise noted)

				MIN	MAX	UNIT
V <sub>IN</sub>	Input voltage	Input voltage				V
V <sub>ON</sub>	ON voltage			0	5.5	V
V <sub>OUT</sub>	Output voltage				$V_{IN}$	V
V <sub>IH, ON</sub>	High-level input voltage, ON	V <sub>IN</sub> = 1 V t	5.5 V	1	5.5	V
V <sub>IL, ON</sub>	Low-level input voltage, ON	V <sub>IN</sub> = 1 V t	5.5 V	0	0.5	V
T <sub>A</sub>	Operating free-air temperature <sup>(1)</sup>			-40	105	°C
C <sub>IN</sub>	Input Capacitor			1 (2)		μF

<sup>(1)</sup> In applications where high power dissipation and/or poor package thermal resistance is present, the maximum ambient temperature may have to be derated. Maximum ambient temperature  $[T_{A(max)}]$  is dependent on the maximum operating junction temperature  $[T_{J(MAX)}]$ , the maximum power dissipation of the device in the application  $[P_{D(MAX)}]$ , and the junction-to-ambient thermal resistance of the part-package in the application  $(\theta_{JA})$ , as given by the following equation:  $T_{A(MAX)} = T_{J(MAX)} - (\theta_{JA} \times P_{D(MAX)})$ .

(2) See the Application and Implementation section.

#### 6.4 Thermal Information

		TPS22918-Q1	
	THERMAL METRIC (1)	DBV (SOT-23)	UNIT
		6 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	183.2	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	151.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	34.1	°C/W
ΨЈТ	Junction-to-top characterization parameter	37.2	°C/W
ΨЈВ	Junction-to-board characterization parameter	33.6	°C/W

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

<sup>(3)</sup> Assumes 12-K power-on hours at 100% duty cycle. This information is provided solely for your convenience and does not extend or modify the warranty provided under TI's standard terms and conditions for TI's semiconductor products.



### 6.5 Electrical Characteristics

Unless otherwise noted, the specification in the following table applies over the following operating ambient temperature  $-40^{\circ}\text{C} \le T_A \le +105^{\circ}\text{C}$  (full). Typical values are for  $T_A = 25^{\circ}\text{C}$ .

	PARAMETER	TEST CON	IDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
			V <sub>IN</sub> = 5.5 V			9.2	16	
			V <sub>IN</sub> = 5 V			8.7	16	
I <sub>Q, VIN</sub>	O.::	$V_{ON} = 5 \text{ V}, I_{OUT}$	V <sub>IN</sub> = 3.3 V	4000 to .40500		8.3	15	^
	Quiescent current	= 0 A	V <sub>IN</sub> = 1.8 V	-40°C to +105°C		10.2	17	μA
			V <sub>IN</sub> = 1.2 V			9.3	16	
			V <sub>IN</sub> = 1 V			8.9	15	
			$V_{IN} = 5.5 \ V$	-40°C to +105°C		0.5	5	
			$V_{IN} = 5 V$	-40°C to +105°C		0.5	4.5	
	Shutdown current	V <sub>ON</sub> = 0 V, V <sub>OUT</sub> = 0 V	$V_{IN} = 3.3 \ V$	-40°C to +105°C		0.5	3.5	
SD, VIN	Shuldown current	= 0 V	$V_{IN} = 1.8 \ V$	-40°C to +105°C		0.5	2.5	μA
			V <sub>IN</sub> = 1.2 V	-40°C to +105°C		0.4	2	
			V <sub>IN</sub> = 1 V	-40°C to +105°C		0.4	2	
I <sub>ON</sub>	ON pin input leakage current	V <sub>IN</sub> = 5.5 V, I <sub>OUT</sub>	= 0 A	-40°C to +105°C			0.1	μA
		.,	000 4	25°C		51	59	
		$V_{IN} = 5.5 \text{ V}, I_{OUT} = -200 \text{ mA}$		-40°C to +105°C			78	mΩ
		V <sub>IN</sub> = 5 V, I <sub>OUT</sub> = -200 mA		25°C		52	59	
				-40°C to +105°C			79	
		V <sub>IN</sub> = 4.2 V, I <sub>OUT</sub> = -200 mA		25°C		52	59	
				-40°C to +105°C			79	
		V <sub>IN</sub> = 3.3 V, I <sub>OUT</sub> = -200 mA		25°C		53	59	
<b>.</b>				-40°C to +105°C			80	
R <sub>ON</sub>	On-Resistance	V <sub>IN</sub> = 2.5 V, I <sub>OUT</sub> = -200 mA		25°C		53	61	
				-40°C to +105°C			80	
				25°C		55	65	
		$V_{IN} = 1.8 \text{ V}, I_{OUT}$	= -200 MA	-40°C to +105°C			88	
		V 40V	200 4	25°C		64	77	
		$V_{IN} = 1.2 \text{ V}, I_{OUT}$	= -200 mA	-40°C to +105°C			104	
		\/ <b>4</b> \/ 1	200 1	25°C		71	85	
		$V_{IN} = 1 V, I_{OUT} =$	–∠UU MA	-40°C to +105°C			116	
V <sub>HYS</sub>	ON pin hysteresis	V <sub>IN</sub> = 1 V to 5.5 \	/	-40°C to +105°C		107		mV
				25°C		24		
		$V_{IN} = 5 V, V_{ON} =$	υV	-40°C to +105°C			30	
_	Output pull down	$V_{IN} = 3.3 \text{ V}, V_{ON}$	= 0 V	25°C		25		^
$R_{PD}$	resistance			-40°C to +105°C			35	Ω
		V <sub>IN</sub> = 1.8 V, V <sub>ON</sub>	= 0 V	25°C		45		
				-40°C to +105°C			60	

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### 6.6 Switching Characteristics

See timing test circuit in Figure 21 (unless otherwise noted) for references to external components used for the test condition in the switching characteristics table. Switching characteristics shown below are only valid for the power-up sequence where VIN is already in steady state condition before the ON pin is asserted high. Test Conditions:  $V_{ON} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

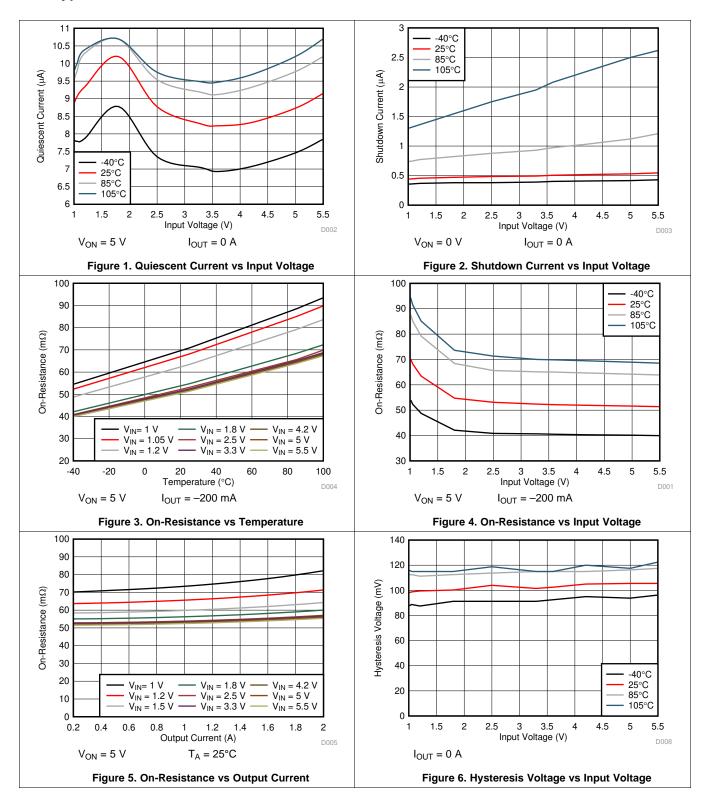
	PARAMETER	TEST CONDITION	MIN TYP	MAX	UNIT
V <sub>IN</sub> =	5 V		,		
t <sub>ON</sub>	Turnon time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	1950		μs
t <sub>OFF</sub>	Turnoff time	$R_L = 10 \ \Omega, \ C_{IN} = 1 \ \mu F, \ C_{OUT} = 0.1 \ \mu F, \ CT = 1000 \ pF$	2		μs
t <sub>R</sub>	V <sub>OUT</sub> rise time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	2540		μs
t <sub>F</sub>	V <sub>OUT</sub> fall time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	2		μs
t <sub>D</sub>	Delay time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	690		μs
V <sub>IN</sub> =	3.3 V				
t <sub>ON</sub>	Turnon time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	1430		μs
t <sub>OFF</sub>	Turnoff time	$R_L = 10 \ \Omega, \ C_{IN} = 1 \ \mu F, \ C_{OUT} = 0.1 \ \mu F, \ CT = 1000 \ pF$	2		μs
t <sub>R</sub>	V <sub>OUT</sub> rise time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	1680		μs
t <sub>F</sub>	V <sub>OUT</sub> fall time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 $p$ F	2		μs
$t_D$	Delay time	$R_L = 10 \ \Omega, \ C_{IN} = 1 \ \mu F, \ C_{OUT} = 0.1 \ \mu F, \ CT = 1000 \ pF$	590		μs
V <sub>IN</sub> =	1.8 V				
t <sub>ON</sub>	Turnon time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	965		μs
t <sub>OFF</sub>	Turnoff time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 $p$ F	2		μs
t <sub>R</sub>	V <sub>OUT</sub> rise time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	960		μs
t <sub>F</sub>	V <sub>OUT</sub> fall time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	2		μs
t <sub>D</sub>	Delay time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	480		μs
V <sub>IN</sub> =	1 V		<u>.</u>		
t <sub>ON</sub>	Turnon time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	725		μs
t <sub>OFF</sub>	Turnoff time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 pF	3		μs
t <sub>R</sub>	V <sub>OUT</sub> rise time	$R_L$ = 10 Ω, $C_{IN}$ = 1 μF, $C_{OUT}$ = 0.1 μF, $CT$ = 1000 pF	560		μs
t <sub>F</sub>	V <sub>OUT</sub> fall time	$R_L$ = 10 $\Omega$ , $C_{IN}$ = 1 $\mu$ F, $C_{OUT}$ = 0.1 $\mu$ F, $CT$ = 1000 $p$ F	2		μs
t <sub>D</sub>	Delay time	$R_L = 10 \Omega$ , $C_{IN} = 1 \mu F$ , $C_{OUT} = 0.1 \mu F$ , $CT = 1000 pF$	430		μs

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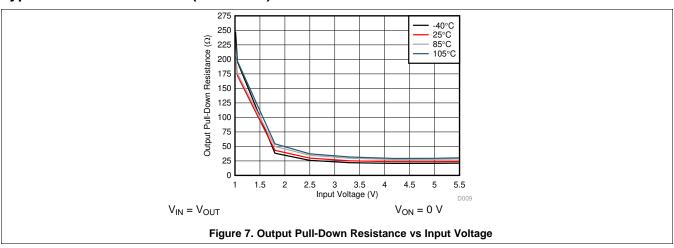


## 6.7 Typical DC Characteristics



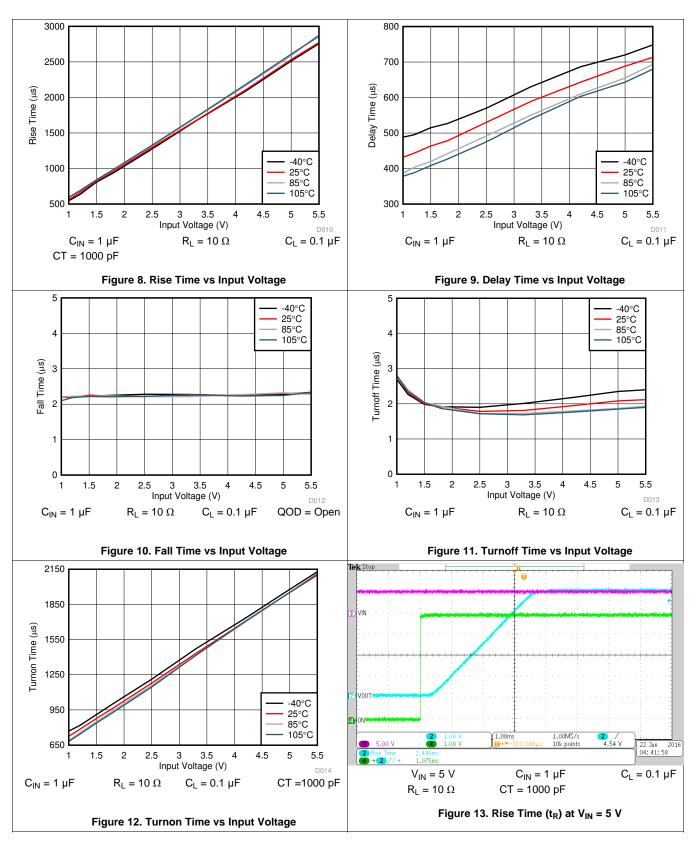


# **Typical DC Characteristics (continued)**



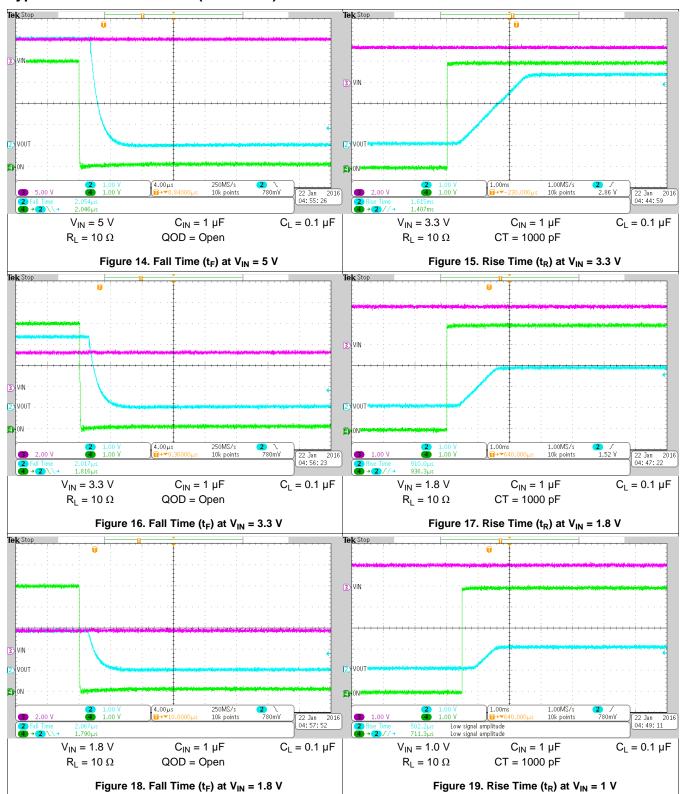


## 6.8 Typical AC Characteristics



### TEXAS INSTRUMENTS

### **Typical AC Characteristics (continued)**

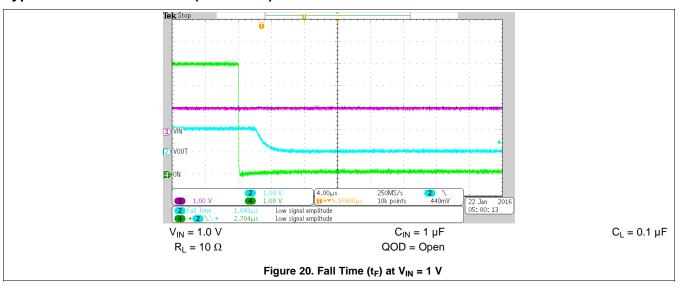


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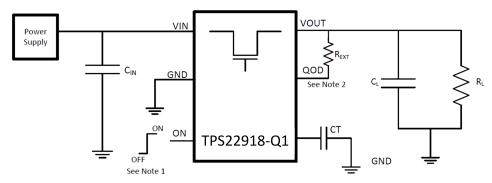


# **Typical AC Characteristics (continued)**





### 7 Parameter Measurement Information



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- (1) Rise and fall times of the control signal is 100 ns.
- (2) Turnoff times and fall times are dependent on the time constant at the load. For TPS22918-Q1, the internal pull-down resistance  $R_{PD}$  is enabled when the switch is disabled. The time constant is  $(R_{QOD} \parallel R_L) \times C_L$  where  $R_{QOD}$  equals  $R_{PD} + R_{EXT}$ .

Figure 21. Test Circuit

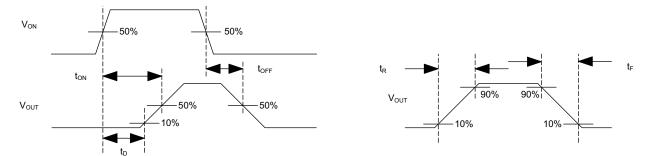


Figure 22. Timing Waveforms



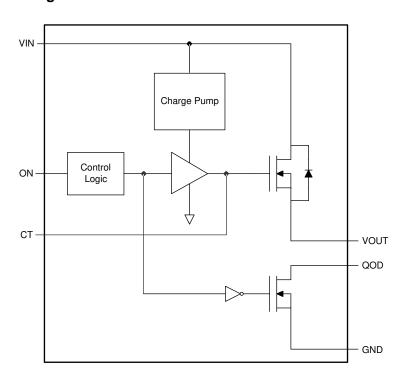
### 8 Detailed Description

#### 8.1 Overview

The TPS22918-Q1 is a 5.5-V, 2-A load switch in a 6-pin SOT-23 package. To reduce voltage drop for low voltage and high current rails, the device implements a low resistance N-channel MOSFET which reduces the drop out voltage through the device.

The device has a configurable slew rate which helps reduce or eliminate power supply droop because of large inrush currents. Furthermore, the device features a QOD pin, which allows to configure the discharge rate of VOUT once the switch is disabled. During shutdown, the device has very low leakage currents, thereby reducing unnecessary leakages for downstream modules during standby. Integrated control logic, driver, charge pump, and output discharge FET eliminates the need for any external components, which reduces solution size and bill of materials (BOM) count.

#### 8.2 Functional Block Diagram



#### 8.3 Feature Description

#### 8.3.1 On and Off Control

The ON pin controls the state of the switch. ON is active high and has a low threshold, making it capable of interfacing with low-voltage signals. The ON pin is compatible with standard GPIO logic threshold. It can be used with any microcontroller with 1 V or higher GPIO voltage. This pin cannot be left floating and must be driven either high or low for proper functionality.

### 8.3.2 Quick Output Discharge (QOD)

The TPS22918-Q1 includes a QOD feature. The QOD pin can be configured in one of three valid ways:

- QOD pin shorted to VOUT pin. Using this method, the discharge rate after the switch becomes disabled is controlled with the value of the internal resistance R<sub>PD</sub>. The value of this resistance is listed in the *Electrical Characteristics* table.
- QOD pin connected to VOUT pin using an external resistor R<sub>EXT</sub>. After the switch becomes disabled, the
  discharge rate is controlled by the value of the total resistance of the QOD. To adjust the total QOD
  resistance, Equation 1 can be used.

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(1)



### Feature Description (continued)

 $R_{QOD} = R_{PD} + R_{EXT}$ 

Where:

- R<sub>OOD</sub> is the total output discharge resistance
- R<sub>PD</sub> is the internal pulldown resistance
- R<sub>EXT</sub> is the external resistance placed between the VOUT and QOD pin.

QOD pin is unused and left floating. Using this method, there is no quick output discharge functionality, and the output remains floating after the switch is disabled.

The fall times of the device depend on many factors including the total resistance of the QOD, VIN, and the output capacitance. When QOD is shorted to VOUT, the fall time changes over VIN as the internal RPD varies over V<sub>IN</sub>. To calculate the approximate fall time of V<sub>OUT</sub> for a given R<sub>QOD</sub>, use Equation 2 and Table 1.

$$V_{CAP} = V_{IN} \times e^{-t/\tau}$$

Where:

1

- V<sub>CAP</sub> is the voltage across the capacitor (V)
- t is the time since power supply removal (s)
- $\tau$  is the time constant equal to R<sub>QOD</sub> × C<sub>L</sub>

resistance. See Table 1 for QOD fall times.

(2)The fall times' dependency on V<sub>IN</sub> becomes minimal as the QOD value increases with additional external

FALL TIME ( $\mu$ s) 90% - 10%,  $C_{IN}$  = 1  $\mu$ F,  $I_{OUT}$  = 0 A ,  $V_{ON}$  = 0  $V^{(1)}$  $T_A = 85^{\circ}C$  $T_A = 25^{\circ}C$ V<sub>IN</sub> (V)  $C_L = 1 \mu F$  $C_L = 10 \mu F$  $C_L = 100 \mu F$  $C_L = 1 \mu F$  $C_L = 10 \mu F$  $C_L = 100 \mu F$ 5.5 42 190 1880 40 210 2150 5 43 200 1905 45 220 2200 47 2150 260 2515 3.3 230 50 2.5 58 300 2790 60 345 3290 1.8 75 430 4165 80 490 4950 1.2 1035 135 955 9910 135 10980

19625

Table 1. QOD Fall Times

#### 8.3.2.1 QOD when System Power is Removed

230

1830

The adjustable QOD can be used to control the power down sequencing of a system even when the system power supply is removed. When the power is removed, the input capacitor discharges at V<sub>IN</sub>. Past a certain V<sub>IN</sub> level, the strength of the R<sub>PD</sub> is reduced. If there is still remaining charge on the output capacitor, this results in longer fall times. For further information regarding this condition, see the Shutdown Sequencing During Unexpected System Power Loss section.

#### 8.3.2.2 Internal QOD Considerations

Special considerations must be taken when using the internal R<sub>PD</sub> by shorting the QOD pin to the VOUT pin. The internal R<sub>PD</sub> is a pulldown resistance designed to quickly discharge a load after the switch has been disabled. Care must be used to ensure that excessive current does not flow through R<sub>PD</sub> during discharge so that the maximum T<sub>J</sub> of 150°C is not exceeded. When using only the internal R<sub>PD</sub> to discharge a load, the total capacitive load must not exceed 200 µF. Otherwise, an external resistor, R<sub>EXT</sub>, must be used to ensure the amount of current flowing through R<sub>PD</sub> is properly limited and the maximum T<sub>J</sub> is not exceeded. To ensure the device is not damaged, the remaining charge from C<sub>1</sub> must decay naturally through the internal QOD resistance and must not be driven.

Product Folder Links: TPS22918-Q1

1800

19270

210

<sup>(1)</sup> Typical values with QOD shorted to VOUT

(3)



#### 8.3.3 Adjustable Rise Time (CT)

A capacitor to GND on the CT pin sets the slew rate for each channel. The capacitor to GND on the CT pin must be rated for 25 V and above. An approximate formula for the relationship between CT and slew rate is shown in Equation 3.

 $SR = 0.55 \times CT + 30$ 

#### where

- SR is the slew rate (in μs/V)
- CT is the capacitance value on the CT pin (in pF)
- The units for the constant 30 are  $\mu$ s/V. The units for the constant 0.55 are  $\mu$ s/(V × pF)

Equation 3 accounts for 10% to 90% measurement on  $V_{OUT}$  and does not apply for CT less than 100 pF. Use Table 2 to determine rise times for when CT is greater or equal to 100 pF.

Rise time can be calculated by multiplying the input voltage by the slew rate. Table 2 contains rise time values measured on a typical device.

CTx (pF)	RISE TIME (µs) 10% - 90%, $C_L$ = 0.1 µF, $C_{IN}$ = 1 µF, $R_L$ = 10 $\Omega$ Typical values at 25°C with a 25-V X7R 10% ceramic capacitor on CT						СТ
. ,	VIN = 5 V	VIN = 3.3 V	VIN = 2.5 V	VIN = 1.8 V	VIN = 1.5 V	VIN = 1.2V	VIN = 1.0 V
0	135	95	75	60	50	45	40
220	650	455	350	260	220	185	160
470	1260	850	655	480	415	340	300
1000	2540	1680	1300	960	810	660	560
2200	5435	3580	2760	2020	1715	1390	1220
4700	12050	7980	6135	4485	3790	3120	2735
10000	26550	17505	13460	9790	8320	6815	5950

Table 2. Rise Time Table

As the voltage across the capacitor approaches the capacitor rated voltage, the effective capacitance reduces. Depending on the dielectric material used, the voltage coefficient changes. See Table 3 for the recommended minimum voltage rating for the CT capacitor.

Table 3. Recommended CT Capacitor Voltage Rating

V <sub>IN</sub> (V)	RECOMMENDED CT CAPACITOR VOLTAGE RATING (V) <sup>(1)</sup>
1 V to 1.2 V	10
1.2 V to 4 V	16
4 V to 5.5 V	20

<sup>(1)</sup> If using  $V_{IN} = 1.2 \text{ V}$  or 4 V, it is recommended to use the higher voltage rating.

### 8.4 Device Functional Modes

Table 4 describes the connection of the VOUT pin depending on the state of the ON pin.

**Table 4. VOUT Connection** 

ON	QOD Configuration	TPS22918-Q1				
L	QOD pin connected to VOUT with R <sub>EXT</sub>	GND (via R <sub>EXT</sub> + R <sub>PD</sub> )				
L	QOD pin tied to VOUT directly	GND (via R <sub>PD</sub> )				
L	QOD pin left open	Open				
Н	Any valid QOD configuration	VIN				



### 9 Application and Implementation

#### NOTE

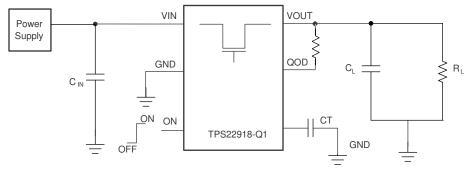
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 9.1 Application Information

This section highlights some of the design considerations when implementing this device in various applications. A PSPICE model for this device is also available in the product page of this device on www.ti.com (See the *Device Support* section for more information).

### 9.2 Typical Application

This typical application demonstrates how the TPS22918-Q1 can be used to power downstream modules.



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Figure 23. Typical Application Schematic

#### 9.2.1 Design Requirements

For this design example, use the input parameters listed in Table 5.

Table 5. Design Parameter

DESIGN PARAMETER	EXAMPLE VALUE
$V_{IN}$	5 V
Load current	2 A
$C_L$	22 uF
t <sub>F</sub>	4 ms
Maximum acceptable inrush current	400 mA



#### 9.2.2 Detailed Design Procedure

#### 9.2.2.1 Input Capacitor (C<sub>IN</sub>)

To limit the voltage drop on the input supply caused by transient in-rush currents when the switch turns on into a discharged load capacitor or short-circuit, a capacitor must be placed between VIN and GND. A 1  $\mu$ F ceramic capacitor,  $C_{IN}$ , placed close to the pins, is usually sufficient. Higher values of  $C_{IN}$  can be used to further reduce the voltage drop during high-current application. When switching heavy loads, it is recommended to have an input capacitor about 10 times higher than the output capacitor to avoid excessive voltage drop.

#### 9.2.2.2 Output Capacitor (C<sub>1</sub>) (Optional)

Becuase of the integrated body diode in the MOSFET, a  $C_{IN}$  greater than  $C_L$  is highly recommended. A  $C_L$  greater than  $C_{IN}$  can cause  $V_{OUT}$  to exceed  $V_{IN}$  when the system supply is removed. This could result in current flow through the body diode from VOUT to VIN. A  $C_{IN}$  to  $C_L$  ratio of 10 to 1 is recommended for minimizing  $V_{IN}$  dip caused by inrush currents during startup.

### 9.2.2.3 Shutdown Sequencing During Unexpected System Power Loss

Microcontrollers and processors often have a specific shutdown sequence in which power must be removed. Using the adjustable Quick Output Discharge function of the TPS22918-Q1, adding a load switch to each power rail can be used to manage the power down sequencing in the event of an unexpected system power loss (battery removal). To determine the QOD values for each load switch, first confirm the power down order of the device this is wished to power sequence. Be sure to check if there are voltage or timing margins that must be maintained during power down. Next, refer to Table 1 in the *Quick Output Discharge (QOD)* section to determine appropriate  $C_{OUT}$  and  $R_{QOD}$  values for each power rail's load switch so that the load switches' fall times correspond to the order in which they need to be powered down. In the above example, make sure this power rail's fall time to be 4 ms. Using Equation 2, to determine the appropriate  $R_{QOD}$  to achieve our desired fall time. Because fall times are measured from 90% of  $V_{OUT}$  to 10% of  $V_{OUT}$ , Equation 2 becomes Equation 4.

$$.5 V = 4.5 V \times e^{-(4 \text{ ms}) / (R \times (22 \mu F))}$$
 (4)

$$R_{QQD} = 83.333 \Omega \tag{5}$$

Refer to Figure 7,  $R_{PD}$  at  $V_{IN} = 5$  V is approximately 25  $\Omega$ . Using Equation 1, the required external QOD resistance can be calculated as shown in Equation 6.

$$83.333 \Omega = 25 \Omega + R_{EXT}$$

$$(6)$$

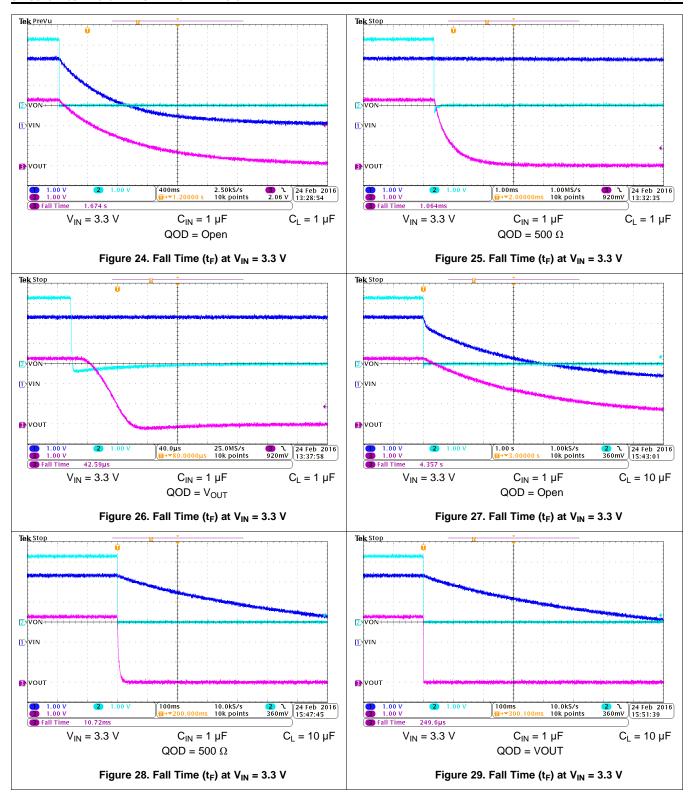
$$R_{\text{FXT}} = 58.333 \,\Omega \tag{7}$$

Figure 24 through Figure 29 are scope shots demonstrating an example of the QOD functionality when power is removed from the device (both ON and VIN are disconnected simultaneously). The input voltage is decaying in all scope shots below.

- Initial V<sub>IN</sub> = 3.3 V
- QOD = Open, 500 Ω, or shorted to VOUT
- $C_1 = 1 \mu F, 10 \mu F$
- V<sub>OUT</sub> is left floating

NOTE:  $V_{IN}$  may appear constant in some figures. This is because the time scale of the scope shot is too small to show the decay of  $C_{IN}$ .





### 9.2.2.4 VIN to VOUT Voltage Drop

The VIN to VOUT voltage drop in the device is determined by the  $R_{ON}$  of the device and the load current. The  $R_{ON}$  of the device depends upon the VIN conditions of the device. Refer to the  $R_{ON}$  specification of the device in the *Electrical Characteristics* table. When the  $R_{ON}$  of the device is determined based upon the VIN conditions, use Equation 8 to calculate the VIN to VOUT voltage drop.

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(9)



 $\Delta V$  is the  $I_{LOAD} \times R_{ON}$ 

#### where

- \( \Delta V \) is the voltage drop from VIN to VOUT
- I<sub>LOAD</sub> is the load current
- R<sub>ON</sub> is the On-resistance of the device for a specific V<sub>IN</sub>

An appropriate  $I_{LOAD}$  must be chosen such that the  $I_{MAX}$  specification of the device is not violated. (8)

#### 9.2.2.5 Inrush Current

Use Equation 9 to determine how much inrush current is caused by the C<sub>1</sub> capacitor.

$$I_{INRUSH} = C_L \times \frac{dV_{OUT}}{dt}$$

#### where

- I<sub>INRUSH</sub> is the amount of inrush caused by C<sub>L</sub>
- C<sub>i</sub> is the capacitance on VOUT
- dt is the output voltage rise time during the ramp up of VOUT when the device is enabled
- $dV_{OLT}$  is the change in  $V_{OLT}$  during the ramp up of VOUT when the device is enabled

The appropriate rise time can be calculated using the design requirements and the inrush current equation. As the rise time (measured from 10% to 90% of  $V_{OUT}$ ) is calculated, this is accounted in the  $dV_{OUT}$  parameter (80% of  $V_{OUT} = 4 \text{ V}$ ) as shown in Equation 10.

$$400 \text{ mA} = 22 \mu \text{F} \times 4 \text{ V/dt}$$
 (10)

$$dt = 220 \,\mu s \tag{11}$$

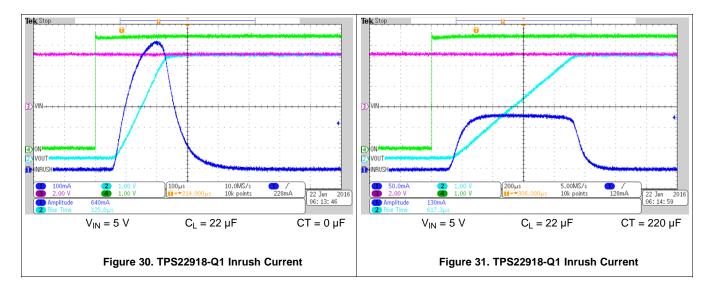
To ensure an inrush current of less than 400 mA, choose a CT value that yields a rise time of more than 220  $\mu$ s. Refering to the Table 2 at  $V_{IN}$  = 5 V, CT = 220  $\mu$ F provides a typical rise time of 650  $\mu$ s. Adding this rise time and voltage into Equation 9, yields Equation 12.

$$I_{\text{Inrush}} = 22 \,\mu\text{F} \times 4 \,\text{V} / 650 \,\mu\text{s}$$
 (12)

$$I_{lnrush} = 135 \text{ mA} \tag{13}$$

This inrush current can be seen in the *Application Curves* section. An appropriate  $C_L$  value must be placed on VOUT such that the  $I_{MAX}$  and  $I_{PLS}$  specifications of the device are not violated.

### 9.2.3 Application Curves



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## 10 Power Supply Recommendations

The TPS22918-Q1 is designed to operate from a VIN range of 1 V to 5.5 V. This supply must be well regulated and placed as close to the device terminal as possible with the recommended 1- $\mu$ F bypass capacitor. If the supply is located more than a few inches from the device terminals, additional bulk capacitance may be required in addition to the ceramic bypass capacitors. If additional bulk capacitance is required, an electrolytic, tantalum, or ceramic capacitor of 1  $\mu$ F may be sufficient.

### 11 Layout

#### 11.1 Layout Guidelines

- VIN and VOUT traces must be as short and wide as possible to accommodate for high current.
- The VIN pin must be bypassed to ground with low ESR ceramic bypass capacitors. The typical recommended bypass capacitance is 1 μF ceramic with X5R or X7R dielectric. This capacitor must be placed as close to the device pins as possible.
- The VOUT pin must be bypassed to ground with low ESR ceramic bypass capacitors. The typical recommended bypass capacitance is one-tenth of the VIN bypass capacitor of X5R or X7R dielectric rating. This capacitor must be placed as close to the device pins as possible.

### 11.2 Layout Example

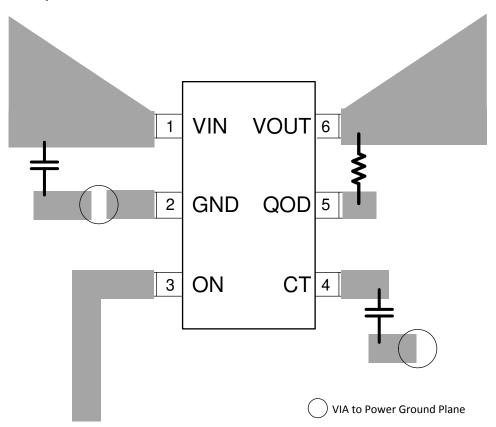


Figure 32. Recommended Board Layout

### 11.3 Thermal Considerations

For best performance, all traces must be as short as possible. To be most effective, the input and output capacitors must be placed close to the device to minimize the effects that parasitic trace inductances may have on normal and short-circuit operation. Using wide traces for VIN, VOUT, and GND helps minimize the parasitic electrical effects along with minimizing the case to ambient thermal impedance.



### Thermal Considerations (continued)

The maximum IC junction temperature must be restricted to 150°C under normal operating conditions. To calculate the maximum allowable dissipation,  $P_{D(max)}$  for a given output current and ambient temperature, use Equation 14.

$$P_{D(MAX)} = \frac{T_{J(MAX)} - T_A}{\theta_{JA}}$$
(14)

Where:

P<sub>D(MAX)</sub> is the maximum allowable power dissipation

T<sub>J(MAX)</sub> is the maximum allowable junction temperature (150°C for the TPS22918-Q1)

T<sub>A</sub> is the ambient temperature of the device

 $\theta_{JA}$  is the junction to air thermal impedance. See the *Thermal Information* table. This parameter is highly dependent upon board layout.

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### 12 Device and Documentation Support

### 12.1 Device Support

#### 12.1.1 Developmental Support

For the TPS22918 PSpice Transient Model, see SLVMBI6.

### 12.2 Documentation Support

#### 12.2.1 Related Documentation

For related documentation see the following:

- TPS22918 5.5-V, 2-A, 50-mΩ On-Resistance Load Switch Evaluation Module, SLVUAP0
- Quiescent Current vs Shutdown Current for Load Switch Power Consumption, SLVA757
- Fundamentals of On-Resistance in Load Switches, SLVA771

### 12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 12.4 Community Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the guick design help you need.

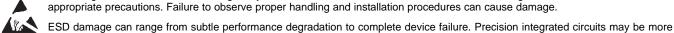
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### 12.5 Trademarks

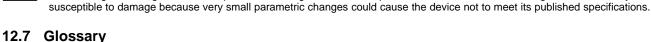
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### 12.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.



SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



www.ti.com 23-May-2025

#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TPS22918TDBVRQ1	Active	Production	SOT-23 (DBV)   6	3000   LARGE T&R	Yes	SN	Level-3-260C-168 HR	-40 to 105	13NW
TPS22918TDBVRQ1.A	Active	Production	SOT-23 (DBV)   6	3000   LARGE T&R	Yes	SN	Level-3-260C-168 HR	-40 to 105	13NW
TPS22918TDBVTQ1	Active	Production	SOT-23 (DBV)   6	250   SMALL T&R	Yes	SN	Level-3-260C-168 HR	-40 to 105	13NW
TPS22918TDBVTQ1.A	Active	Production	SOT-23 (DBV)   6	250   SMALL T&R	Yes	SN	Level-3-260C-168 HR	-40 to 105	13NW

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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#### OTHER QUALIFIED VERSIONS OF TPS22918-Q1:

<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# **PACKAGE OPTION ADDENDUM**

www.ti.com 23-May-2025

• Catalog : TPS22918

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product



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### TAPE AND REEL INFORMATION

NSTRUMENTS





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS22918TDBVRQ1	SOT-23	DBV	6	3000	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
TPS22918TDBVRQ1	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS22918TDBVTQ1	SOT-23	DBV	6	250	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
TPS22918TDBVTQ1	SOT-23	DBV	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3



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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS22918TDBVRQ1	SOT-23	DBV	6	3000	190.0	190.0	30.0
TPS22918TDBVRQ1	SOT-23	DBV	6	3000	210.0	185.0	35.0
TPS22918TDBVTQ1	SOT-23	DBV	6	250	190.0	190.0	30.0
TPS22918TDBVTQ1	SOT-23	DBV	6	250	210.0	185.0	35.0



SMALL OUTLINE TRANSISTOR



#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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